

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,765	CHAN ET AL.	
Examiner	Art Unit	
Tyrone W. Smith	2837	

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SEARCHED					
Class	Subclass	Date	Examiner		
318	138 439 254 700 685 696	3/14/2006	TS		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
318	138 439	3/14/2006	TS	
318	254 700	3/14/2006	TS	
318	685 696	3/14/2006	TS	
	earch (see ched)	3/14/2006	TS	

SEARCH N (INCLUDING SEARC		)
	DATE	EXMR
United States Patent Databxe Derwent Japanese European Non-patent Literature	3/14/2006	TS
East Search (see attached)	3/14/2006	TS
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